

Securing Scan Design Using Lock & Key Technique

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Abstract

Scan test has been a common and useful method for testing VLSI designs due to the high controllability and observability it provides. These same properties have recently been shown to also be a security threat to the intellectual property on a chip [1]. In order to defend from scan based attacks, we present the Lock & Key technique. Our proposed technique provides security while not negatively impacting the design's fault coverage. This technique requires only that a small area overhead penalty is incurred for a significant return in security. Lock & Key divides the already present scan chain into smaller subchains of equal length that are controlled by an internal test security controller. When a malicious user attempts to manipulate the scan chain, the test security controller goes into insecure mode and enables each subchain in an unpredictable sequence making controllability and observability of the circuit under test very difficult. We will present and analyze the design of the Lock & Key technique to show that this is a flexible option to secure scan designs for various levels of security.

1. Introduction

Scan has been generally accepted as the standard method of testing chips due to the high fault coverage and low overhead. Including scan while designing the chip requires one additional pin to the primary I/O for the test control pin (TC) [2]. Internally, there is little impact on the design since the standard flip-flops (FFs) are exchanged with scan flip-flops (SFFs), which are then linked to one another creating a scan chain. TC selects between functional and test mode operation. SFFs carry the additional overhead of a single two-to-one multiplexer when compared to the standard flip-flop. TC controls each multiplexer choosing between the normal mode input of the flip-flop or the output of the previous scan flip-flop in the chain. Due to the additional multiplexer, normal mode performance could potentially be hindered since the output of the combinational logic blocks are not directly connected to the input of the FFs.

The flip-flop registers make up the I/O to the combinational logic blocks in the chip, so test engineers are able to manipulate the values that are input (controllability) and view the output (observability) of each block. This is performed by multiplexing one primary input pin and one primary output pin as the scan in (SI) pin and scan out (SO) pin, respectively. Using the SI pin while TC is enabled, a test pattern is scanned in to the scan chain as dictated by the system clock [2]. When the entire pattern is scanned in, TC is disabled and the chip is run in normal mode for one cycle storing the responses back into the SFFs. TC is again enabled to scan out the response while at the same time scanning in a new test pattern to check for new faults the previous pattern was not able to detect. Using this method of test, sequential logic essentially becomes combinational logic during test. Creating test patterns that achieve high fault coverage is a much easier task for combinational logic than it is for sequential logic significantly speeding up the test pattern generation process [2].

Security has become a concern in the design and test of chips within recent years [3][4][5]. This has become more apparent with the advent of cryptochips [6]. Cryptochips perform encryption and decryption algorithms at the circuit level. Many researchers have been able to show that these chips are highly vulnerable to various power analysis [7], timing [8], and fault injection [9][10] attacks if not specifically designed with countermeasures in mind. If not considered carefully, strong encryption

algorithms that would take years to crack by brute force can otherwise be crippled in a manner of weeks, days, or even hours through these side channel attacks.

Currently, the main objective in testing has been to control and observe a chip as much as possible in order to achieve high fault coverage on the CUT. As useful as these properties are for testing, they are completely contradictory to the objectives of security on a chip. In order to protect a chip from malicious users, a chip must reveal as little as possible while still be usable by the end-user and give a test engineer as much access to the chip as possible.

Recently, scan test has been proven a security risk to the intellectual property on the chip [1][11][12][13]. Yang et al. [1] were able to simulate an attack on the scan chain of a DES cryptochip to reveal the secret key with using only three plaintexts. Although the scan chains have only been exploited to find the secret key of a cryptochip, it is just as easy to uncover proprietary intellectual property (IP) through scan chains. Scan chains allow high controllability and observability to vital registers revealing a lot more than the fabrication defects in a chip.

In order to prevent IP theft, security measures must be implemented during the design phase of the manufacturing process. In this paper, we propose Lock & Key security in order to prevent aggressive users from maliciously attacking the scan chains to reveal vital information about the chip. Our low overhead security solution against scan chain side-channel attacks minimizes the controllability and observability of the scan chain when an unauthorized user makes an attempt to access them by switching into insecure mode. We divide the scan chain into smaller subchains of equal length and randomly select the subchain when an unwanted user attempts to manipulate the scan chains. This prevents malicious users from predicting where in the scan chain the stimuli on SI goes and where the response from SO comes from.

This paper is organized as follows: In Section 2, we will discuss the differences and the potential compromises that are necessary for testability and security and how these two relate to hacking. Section 3 will discuss some prior work performed in the field of chip security. We will then propose and discuss our method of Lock & Key security in Section 4. Finally, we will conclude our discussion in Section 5.

2. Testability, security and hacking

Testability and security inherently contradict each other. The testability of a chip can be defined by the amount of controllability and observability the test engineer is granted. The higher degree of controllability and observability allowed, the easier it is to test the CUT. The test is not only easier to perform, but the result of the test becomes more reliable due to a higher fault coverage.

Security ensures that anything in a circuit is safely stored within it. The most common manner of providing security is to hide the information behind some form of recognition that would be able to tell a valid user from an attacker. Modern day security in all realms use this method to protect vital belongings, whether it is a security code for a home, retinal scanner for a lab, or encryption key for information. Security relies on making information obscure and difficult to figure out.

When trying to relate testability and security together in chip design, security is clearly contradicted by testability. By designing for testability, a designer is essentially leaking all information about the chip through the use of scan test. If the aim of designing a chip is security, it is very difficult to justify the amount of controllability and observability that testability aims to provide because of these leaks. It is also necessary, however, to ensure the chip will function properly through testing in a fast and reliable manner. The only truly system secure from any leaks is one without any controllable inputs nor observable outputs keeping it a completely black box, but this is absurd from both a testability and a usability standpoint.

Much of this concern over chip security would not be necessary unless the IP needed to be protected from malicious users and hackers. There are many hackers in the world with many different motivations. They range from the noble, attempting make their fellow developers aware of their pitfalls, the malicious, stealing information that does not rightfully belong to them, and simply the curious [14].

The skill-set of hackers vary as much as their intentions. We have categorized hackers into the following classes:

- 1) The *Beginner* is as the name suggests. This class is just getting started, possibly out of curiosity.
- 2) The *Independent* class is more serious about what they do. The amount of knowledge available is great and the amount of resources is fairly large. This class may be more of a threat than some may give them credit.
- 3) The *Business* class hackers are essentially performing business espionage. They are trying to get a step ahead of their competition even if it is unethical behavior.
- 4) *Government* hackers for the most part participate in these actions out of the security of their nation. If there is a system claiming to be unbreakable, they intend to break it for their own security.

The different classes of hackers tend to correlate with the amount of effort they are willing to put into a job and the amount of effort that is necessary to secure the device under attack. If the hacker is only a beginner, it can be assumed that unless the attack is available online or in a book the hacker will give up with little effort. The chip designer then has little to worry about when designing a circuit. A simple encoding scheme may suffice. The next level of the hacker hierarchy may require much more effort to deter the hacker. A strong encryption algorithm must be used. Protecting IP from the business hacker is very difficult due to the high availability of money and knowledge, but if the hacking process takes too long, their product will be released too late to compete with other businesses. It is next to impossible to secure a system against government hacking due to the almost unlimited resources at their disposal. The amount of overhead is quite different when trying to protect a chip from the many hacker classes. With each step up the hierarchy the cost and amount of overhead continues to increase just to obscure the side-channel leaks a little more.

We will mainly focus our efforts on securing the scan chains that make the lives of test engineers considerably easier. This is not an easy task since the testability of a CUT is dependent on the amount of controllability and observability allowed through the scan chains. It is quite likely hackers have a fair amount of knowledge of the chip they are attacking. It is not difficult to learn the pin-outs and high level timing of the circuit under attack since these are often provided in the specifications from the chip manufacturer [1].

Testability and security have what appears to be a mutually exclusive relationship. It is very difficult to satisfactorily meet the needs of both specifications. A middle ground must be met between the fully controllable and observable CUT and a black box. If one considers the hacker during design, a clearer relationship between testability and security can more easily be concluded. If the designer can target specifically which class he would like to prevent access to, it may be easier to make design compromises between testability and security.

3. Prior work

Implementing encryption algorithms in hardware have revealed quite a few methods to discover the secret keys through side channels. These side channel attacks include differential power analysis [7], timing analysis [8], fault injection [9][10], and most recently scan chain hijacking as demonstrated in [1]. It is also possible to reveal proprietary information through these side channel attacks making these a particularly large concern to companies.

Due to the side channel attacks, a lot of attention has begun to be paid toward the inclusion of security during design. [3] and [4] discuss the importance of using tamper resistant design to prevent such side channel attacks. A VLSI design flow was proposed by [5] that included designing tamper resistant circuits beginning as early as the RTL stage.

Traditional side-channel leaks have often been secured with the use of additional circuitry. Power analysis attacks can be prevented with noise inducing circuitry [7] or applying additional circuitry to hide supply variations [15]. Timing attacks can be prevented by adding additional gates so all operations are performed in the same amount of time or to add random delays to processing time [16]. Finally fault-injection attacks can be detected with additional logic that performs the inverse operation of the original logic to check if the result reproduces the input [17][18].

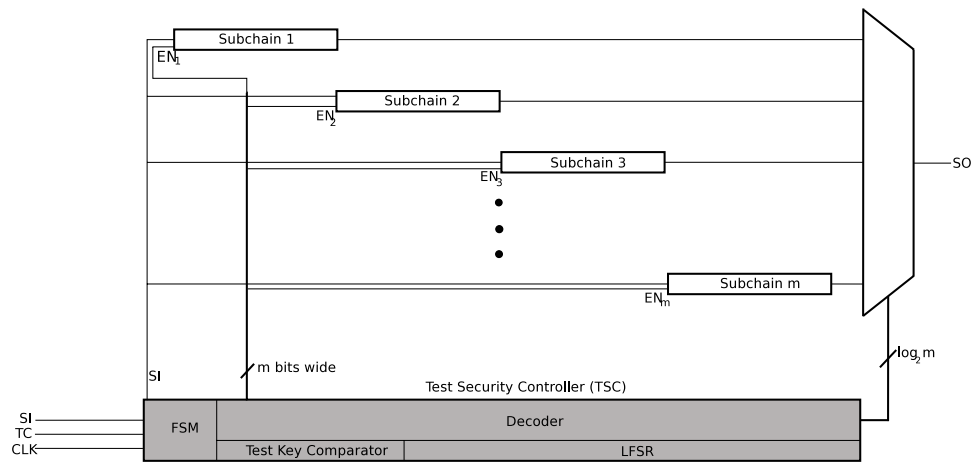


Figure 1. Architecture of lock & key security measure

There has not been much work done that is directly related to the security of scan chains. Most have gotten around the concern by using BIST. In [6], Hafner et al. used BIST to test the entire cryptochip they designed. It provided high fault coverage for both the standard cells and memories, but did not fair nearly as well on the custom designed portions of the chip. Both BIST and boundary scan were used in [19]. The fault coverage still was not nearly as high as what could have been achieved with automatic test pattern generation (ATPG) for scan-based design. Any security sensitive I/O were excluded from the boundary scan.

Work to secure scan designs has only begun recently. An encoding/decoding security scheme has been proposed [12][13], but another more developed method has been presented by [11]. They present a method to modify the scan chains that would internally scramble the values if the test mode was not properly secured. By using an unpredictable random number generator to choose the segment to scan out, it makes comparing the output after each scan out very difficult. Although this will make the output very difficult to interpret for an unauthorized user, it will also create significant delay, routing, and logic overhead since each segment is connected to all other segments in the chain.

4. Lock & key technique

The Lock & Key security measure we are proposing can be used to secure both single and multiple-scan designs. For either case, the scan chain can be divided into smaller equal length subchains. Test vectors are not sequentially shifted into each subchain but rather a linear feedback shift register (LFSR) randomly selects a subchain to be filled. Figure 1 shows a general architecture for the Lock & Key method for single-scan design.

The goal of this method is to prevent those who do not hold the test key from manipulating the scan chain and revealing vital information about the chip. This is ensured by the test security controller (TSC), which consists of a finite state machine (FSM), test key comparator, LFSR, and decoder. There are two states the TSC can be in: *secure* and *insecure* modes. When the CUT is initially reset, the FSM sets the TSC into insecure mode and will remain in this insecure state until TC is enabled. It is only after TC has been enabled for the first time and a test key has been entered that the TSC may exit the insecure state. When a test key is entered and a user has been ensured to be a trusted user, the FSM allows the TSC to enter secure mode.

There are two steps the FSM must take before scanning in a test vector for the first time. When TC is initially enabled, the FSM will first need to check for a correct test key. It will feed the first k bits of the test pattern, which makes up the test key, to the test key comparator. The comparator will then return a pass or fail response to the FSM, which will then decide the next state. If the

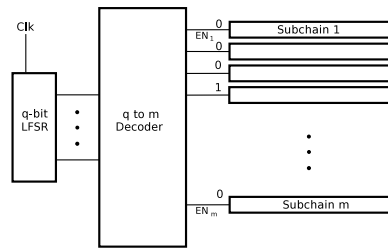


Figure 2. LFSR and decoder in TSC for Lock & Key security

key passes, the FSM will switch the TSC to secure mode allowing predictable operation of the scan chains and will remain in this state until the CUT is reset. Otherwise, the TSC will remain in insecure mode and the behavior of the scan chain will not longer be predictable.

Assuming the test key comparator returned a pass response to the FSM, the next $q = \log_2(m+1)$ bits will then be fed to the LFSR and used as an initial seed, where q is the size of the LFSR and m is the number of subchains being implemented. The seeded LFSR will then use a decoder as an interface to the subchains for a one-hot output, which individually enables each subchain. We will discuss in detail the concept of an enable signal and how it is generated to control subchains in Section 4.3. Assuming l is the length of each subchain, the LFSR/decoder generates the next one-hot output after l clock cycles. Finally, the FSM connects SI to the inputs of the subchains and the test pattern can be shifted into the scan chain. Once the scanning in process is finished for the first round, TC goes low and the CUT will function in normal mode capturing the response in the SFFs. Once the CUT returns to test mode, a new test vector is scanned into the subchains in the same or a new random order, depending on the design, as the previous vector was scanned in. The response is shifted-out at the same time the new pattern is shifted-in.

If the entered key fails, the TSC remains in insecure mode and will seed the LFSR with an unpredictable random seed, essentially locking the scan chains from being used correctly. Since the choice of subchain is pseudo-random due to the LFSR, it is difficult to predict the response on SO if both the seed and the configuration of the LFSR are unknown. Even if the configuration of the LFSR taps are known, if the LFSR is large enough, it is difficult to know the subchain order without first realizing the initial seed. The need for a test key also compounds any attempt made by an unauthorized party to use the scan chain.

Although conceptually similar to scan chain scrambling proposed in [11], this method does not have the requirement of connecting the output of each subchain to the input of all other subchains, which will significantly reduce area overhead. Also, the response shifted out from SO is dependent on the seed and LFSR configuration adding an additional obstacle for the hacker. The possibility of using this method with multiple scan test also provides the advantage of conforming to many design for test tools used in industry.

4.1. Design of lock & key

There are many possible configurations for the LFSR. Although we want the ability to ensure security of the scan chain, we also want the design of the Lock & Key method to be design independent. To prevent the decoder from becoming design dependent, an LFSR with a primitive polynomial configuration will allow the selection of $m = 2^q - 1$ subchains without choosing the same subchain twice before all subchains have been selected once. If subchains are allowed to repeat, the test application time will become significantly longer. Figure 2 shows the LFSR and decoder. Since there is at least one primitive polynomial for all values of q , the LFSR is guaranteed to choose each subchain once before repeating for any length of the LFSR [2].

The choice of a primitive polynomial significantly simplifies the design of the decoder. The decoder can directly translate the output of the LFSR into a run of zeros and single one to directly control each subchain. This method not only shortens design time, but also reduces the area overhead of the TSC as a whole.

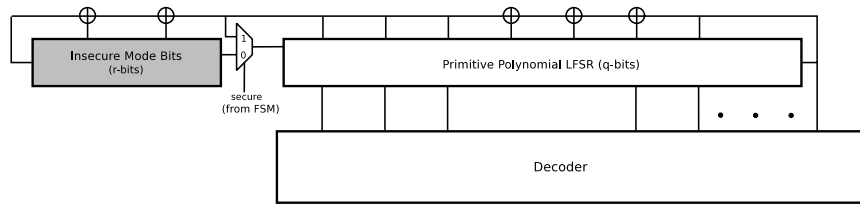


Figure 3. Modifiable LFSR determined by security mode of TSC.

The problem with using a primitive polynomial configuration LFSR is the predictability of its behavior. If the LFSR were to remain unchanged for insecure mode operation, it would not take long to find the order since the order is always the same, only the start and end points would differ. To avoid this predictability, the LFSR configuration must be altered when set to insecure mode. An additional r -bits to the LFSR that are only active when the TSC is insecure easily serve this purpose. Figure 3 shows the LFSR with the additional bits that are only active for insecure mode operation. As can be seen in Figure 3, the additional bits are hidden behind a multiplexer. The output from the LFSR to the input of the decoder does not change. Since the original LFSR only makes up a smaller part of the insecure mode LFSR, repetitively selecting the same subchain multiple times during one test cycle becomes possible, which results in a more complex output. Unlike in secure mode, repetition is not a large concern since we want the output on SO to confuse and obscure the order of the scan chains. To further complicate an attack and to make each test round unique when the TSC is insecure, the FSM can create a new random seed every round.

Another design option when using the LFSR/decoder control in the test security controller is to use an LFSR with a non-primitive polynomial configuration. It is a more design intensive and circuit dependent solution, but provides more security since it does not have the same predictability as the primitive polynomial configured LFSR. The design would use an LFSR of length $r + q$ but only use $q = \log_2(m + 1)$ bits when in a secure state to select a subchain. Unlike the advantage of using a primitive polynomial LFSR, this design does not guarantee each subchain will only be chosen without repetition during a scan-in series and results in an increased test time. A memory element could be used in the decoder that will recall which subchains have been selected during the current scan-in series and use this to make a decision to choose another subchain. Upon entering normal mode to run the test pattern, these memory elements would then be cleared for the next pattern. If the CUT is in insecure mode, the remaining r bits of the LFSR can be used to further randomize the selection made by the decoder. Again, repeating subchains is not a concern since we are trying to confuse and obscure the response being placed on SO.

When applying our Lock & Key technique to multiple scan chain designs, essentially the same principles as single scan designs hold. If the length of the scan chain is long enough, each scan chain is broken down into m subchains, but rather than use a separate TSC for each chain, a single TSC can be used to control all chains. Since each scan chain in multiple scan design would normally be controlled by the same TC, there is no reason for each chain to be controlled by a separate TSC. No more information about the scan design is given away by using multiple scan as opposed to single scan, the only actual difference is in the parallelism for faster testing. If the length of each scan chain is short, they will not be divided into subchains and the Lock & Key technique is used to access and control all chains.

4.2. Analysis of lock & key

The number of subchains needed is completely dependent upon the amount of complexity required to deter hackers. If there are m subchains in the design, the response scanned out on SO can be one of $m!$ possible combinations when in secure mode or up to m^m combinations when in insecure mode. With as few as 15 subchains, an untrusted user that does not have knowledge of the LFSR configuration nor the seed would have more than one trillion unique combinations to choose from in secure mode and more than 15^{15} possible combinations to choose from in insecure mode. A brute

force attempt at resolving the pattern to the location in the chain becomes extremely difficult and continues to increase in difficulty as m increases.

Overall, this method significantly increases the amount of work necessary to mount an attack on the scan chains. The following tasks need to be done by a hacker in order for them to perform a successful attack:

- 1) Hackers must first learn of what security strategy is being used.
- 2) If they figure out the strategy used, then they must find the secret test key for the operation of the chains to be predictable.
- 3) Even if hackers were to be able to discover the test key, hackers must also determine the pseudo-random order that patterns will be scanned in and out.
- 4) If hackers are able to find all this information, an attack can finally be mounted against the CUT while still having to manage with the pseudo-random selection of the subchains.

As discussed in Section 2, it is easier to design a chip when a specific hacker class is targeted. The benefit of Lock & Key security is that it scales easily to the amount of security the designer would like to include. A small TSC with a 4-bit LFSR would be more than suitable to stop a beginner, but increasing the LFSR to 8-bits would potentially be sufficient to prevent some independent hackers from intrusion. As the granularity of each subchain becomes smaller and the number of bits in the LFSR becomes greater, the TSC becomes larger.

We synthesized our Lock & Key technique in Verilog using Synopsys and the Design Analyzer tool [20]. Table 1 shows the number of equivalent gates returned by Design Analyzer for the FSM, test key comparator, LFSR, and decoder with 4-bit, 8-bit, and 12-bit LFSRs. The Lock & Key test security controller grows fairly slowly for a large increase in the number of subchains. The FSM and test key comparator remain a fairly constant size. FSM operation is mostly independent of size of the LFSR. The test key comparator is only dependent upon the size of the test key. For a minimally secure test key length, a length of $k \geq 40$ -bits should be used. For our implementation, we used a 64-bit test key. The size of the test key comparator in Table 1 does not include the additional overhead for on-chip key storage, but we did include it in the final size of the TSC. Only the growth of the LFSR and decoder is of any significance in terms of size, but the number of subchains that can be used exponentially increases with each additional bit. The total size of each LFSR includes the r -bits used for insecure mode operation. We chose to use a constant r value of 4 for all implementations and the primitive polynomials used were from [2].

A 4-bit LFSR can control 15 subchains placing any one of 15^{15} different subchain combinations on SO while insecure. Without prior knowledge, a beginner would have little chance of hacking any vital information from the chip using the scan chain alone. By doubling the size of the LFSR to 8-bits, most independent hackers should be deterred. Increasing the LFSR size again greatly increases the amount of security, but at the cost of a much larger area overhead due to the exponential growth of the decoder. Increasing the size beyond 10-bits should suffice for some businesses, but if they have enough resources to open the package and reverse engineer the layout, any effort to secure the scan chain is inadequate. The same can be said for government hackers attempting to reverse engineer the chip. If the IP is important enough for them to attempt to hack, they will easily be able to pool together the appropriate resources to perform a brute force attack if no other solution is viable. However, we suggest that design engineers use multiple design security techniques to force both business and government hackers to spend more time, money, and other resources.

The components for the TSC are fairly standard and testing it with BIST can provide a fairly high coverage. Testing the TSC would defeat the purpose of the security feature since BIST would only return a pass or fail result as opposed to a pattern response that could potentially be used to expose either the test key or random seed. The other option would be to simply not test the TSC logic at all since it is part of the testing logic for the CUT. This option is similar in nature to the choice of ignoring to test BIST logic due to the fact that if the CUT returns an incorrect result, the chip is faulty regardless of whether the CUT is faulty or the TSC is faulty [2].

The effect of including Lock & Key security on a chip is fairly minimal when used in modern

Table 1. Number of gates in TSC for 4-bit, 8-bit, and 12-bit.

Number of LFSR Bits (q)	Size of FSM	Size of Test Key Comparator	Size of LFSR ($q + r$)	Size of Decoder	Total Size of TSC
4-bit LFSR	113	54	48	25	327
8-bit LFSR	133	54	71	307	652
12-bit LFSR	153	54	91	5432	5817

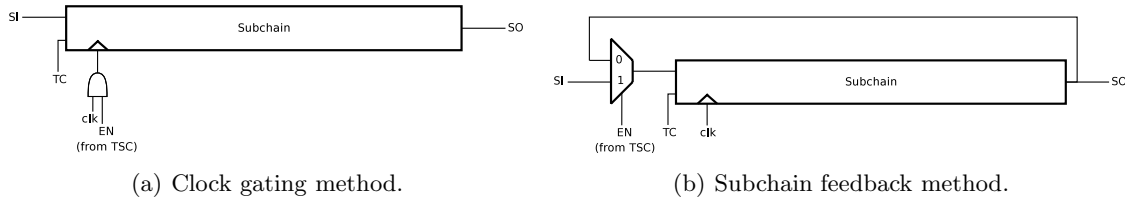


Figure 4. Two subchain modifications to prevent simultaneous normal and test mode operation.

designs. Not only does the TSC logic provide little area overhead, but performance of the chip in normal mode is not affected any more than a circuit with standard scan test. In case of using a primitive polynomial for the LFSR, the affect on test time is also minimal because only a test key and LFSR seed need to be added to the beginning of the test pattern.

4.3. Modification to scan chains

In order for the Lock & Key technique to be effective, an enable signal must be used for each subchain. We cannot treat the enable signal as TC since that would place one subchain into test mode while the remaining subchains are in normal mode, potentially changing all registers that had already been loaded with a new test vector. We introduce two potential solutions that avoid modification of the standard scan cell.

The *Clock Gating* method has been proposed for low power testing in the past [21][22]. We would like to apply the same principle to halt normal operation of the subchains when the enable signal from the TSC is low. In order to do so, this method adds an additional gate that combines the system clock and the enable signals from the TSC to the subchain clock. When the enable signal is high for a particular subchain, the subchain will behave as a normal scan chain with respect to the system clock. When the enable signal is low, the subchain will ignore the system clock and not shift when TC is high. Figure 4(a) shows a gating technique that uses the system clock and the TSC enable signal.

Since this is a small addition, chip area is not severely impacted. It does however affect clock skew and chip performance. This solution is not suited for high performance applications, but does provide the opportunity for low power testing since at most l scan cells would be in transition at any time as opposed to the full length of the scan chain.

Subchain Feedback is the second technique that can be used to avoid simultaneous normal and test mode subchain operation. Figure 4(b) shows an example of the subchain feedback loop. Unlike gating the clock, each subchain still shifts the SFF registers regardless of whether enable is high. By adding a multiplexer to the input of the subchain, the next value to be scanned in can either be from the new test vector if enable is high or from the last register of the subchain when enable is low. Since we assume that the subchains are the same length, maintaining consistent data in each subchain does not become an issue.

This option eliminates the performance problem created by gating the clock, but does not reduce the potential maximum number of transitions when shifting. Since all subchains are shifting regardless of the enable signal, there will still be as many transitions as if one continuous chain were used. There is the need for additional routing for the feedback loop and the multiplexer, but these additions are still fairly small.

5. Conclusion

Scan based designs have been proven to be a significant security risk to the contents of a chip. Without proper security in place, encryption algorithms can be weakened and IP can be stolen. We have proposed the Lock & Key technique as a countermeasure to the method that has been used to expose vital information through the scan chain. Unless the the user is trusted, our technique will cause the scan chain to operate unpredictably and make exploitation very difficult. Design of the technique is flexible and straight forward to implement for varying degrees of security. Until another method of testing a chip can yield the similar coverage as scan based designs with better security, flexible, low-overhead solutions must be included in the design of scan.

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